

Features

- Qualified according to AEC Q101
- CRM G2 SiC MOSFET Technology
- High Blocking Voltage with Low On-Resistance
- High Speed Switching with Low Capacitances
- Avalanche Ruggedness
- Fast Reverse Recovery

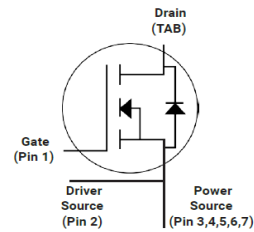
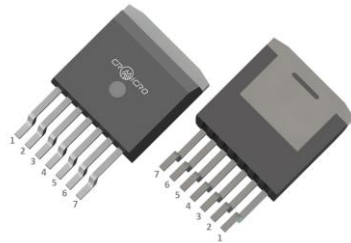
Applications

- Solar Inverters
- High Voltage DC/DC Converters
- On Board Charger(OBC)
- EV Charger

Product Summary

VDS	1200V
R _{DS(on)_typ}	160mΩ
I _D	17A

100% Avalanche Tested



Package Marking and Ordering Information

Part #	Marking	Package	Packing	Qty
CRXSP160M120G2Q	X160M120G2Q	TO-263-7	Reel	800pcs

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V _{DSmax}	1200	V
Continuous drain current V _{GS} =15V, T _C = 25°C V _{GS} =15V, T _C = 100°C	I _D	17 12	A
Pulsed drain current (T _C = 25°C, t _p limited by T _{jmax})	I _{D(pulse)}	43	A
Avalanche energy, single pulse (L=10mH, R _g =25Ω)	E _{AS}	210	mJ
Gate-Source voltage (dynamic) ^{a1}	V _{GSmax}	-10/+22	V
Gate-Source voltage (static) ^{a2}	V _{GSop}	-5/+18	V
Power dissipation (T _C =25°C, T _J =175°C)	P _D	92	W
Operating Junction and Storage Temperature	T _j , T _{stg}	-55...175	°C

a1: When using MOSFET Body Diode V_{GSmax} = -5V/+22V

a2: MOSFET can also safely operate at 0/+18 V

Thermal Resistance

Parameter	Symbol	Value	Unit
Thermal resistance, junction – case. Max	R_{thJC}	1.63	°C/W
Thermal resistance, junction – ambient. Max	R_{thJA}	40	

Electrical Characteristic (at $T_j = 25^\circ\text{C}$, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		

Static Characteristic

Drain-source breakdown voltage	$V_{(BR)DSS}$	1200	-	-	V	$V_{GS}=0V, I_D=250\mu A$
Gate threshold voltage	$V_{GS(th)}$	1.8	-	3.6	V	$V_{DS}=V_{GS}, I_D=2.5mA$
Zero gate voltage drain current	I_{DSS}	-	1	100	μA	$V_{DS}=1200V, V_{GS}=0V$ $T_j=25^\circ\text{C}$
		-	10	-		$T_j=175^\circ\text{C}$
Gate-source leakage current	I_{GSS}	-	-	250	nA	$V_{GS}=20V, V_{DS}=0V$
Drain-source on-state resistance	$R_{DS(on)}$	-	160	208	mΩ	$V_{GS}=15V, I_D=8.5A,$ $T_j=25^\circ\text{C}$
		-	304	-		$T_j=175^\circ\text{C}$
Transconductance	g_{fs}	-	6.6	-	S	$V_{DS}=20V, I_{DS}=8.5A$

Dynamic Characteristic

Internal Gate resistance	R _{G(int)}	-	3.2	-	Ω	f=1MHz
Input Capacitance	C _{iss}	-	659	-	pF	V _{GS} =0V, V _{DS} =1000V, f=1MHz
Output Capacitance	C _{oss}	-	29.5	-		
Reverse Transfer Capacitance	C _{rss}	-	3.6	-		
Coss Stored Energy	E _{oss}	-	16.5	-	uJ	
Gate Total Charge	Q _g	-	36	-	nC	VGS=-5/15V VDS=800V ID=8.5A
Gate-Source charge	Q _{gs}	-	7.5	-		
Gate-Drain charge	Q _{gd}	-	15	-		
Turn-on delay time	t _{d(on)}	-	24	-	ns	VDD=800V,ID=8.5A VGS=-5V/15V, RG=10Ω, L=100uH
Rise time	t _r	-	15.8	-		
Turn-off delay time	t _{d(off)}	-	18.6	-		
Fall time	t _f	-	10	-		
Turn-On Switching Energy	E _(on)	-	174	-	uJ	
Turn Off Switching Energy	E _(off)	-	8.9	-		

Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	V_{SD}	-	2.9	-	V	$V_{GS}=0V, I_F=3.0A$
		-	2.7	-	V	$V_{GS}=0V, I_F=3.0A, T_j=175^{\circ}C$
Continuous Diode Forward Current	I_S	-	-	17	A	$V_{GS}=0V$
Diode pulse Current	$I_{S,pulse}$	-	-	43	A	pulse width t_p limited by T_{jmax}
Body Diode Reverse Recovery Time	t_{rr}	-	36	-	ns	di/dt=1000A/us $I_F=8.5A$ $V_{dd}=800V$ $T_j=25^{\circ}C$
Body Diode Reverse Recovery Charge	Q_{rr}	-	89	-	nC	
Body Diode Peak Reverse Recovery Current	I_{rrm}	-	4.9	-	A	
Body Diode Reverse Recovery Time	t_{rr}	-	47	-	ns	di/dt=1000A/us $I_F=8.5A$ $V_{dd}=800V$ $T_j=175^{\circ}C$
Body Diode Reverse Recovery Charge	Q_{rr}	-	230	-	nC	
Body Diode Peak Reverse Recovery Current	I_{rrm}	-	8.7	-	A	

Typical Performance Characteristics

Fig 1. Output Characteristics ($T_j = -55^\circ\text{C}$)

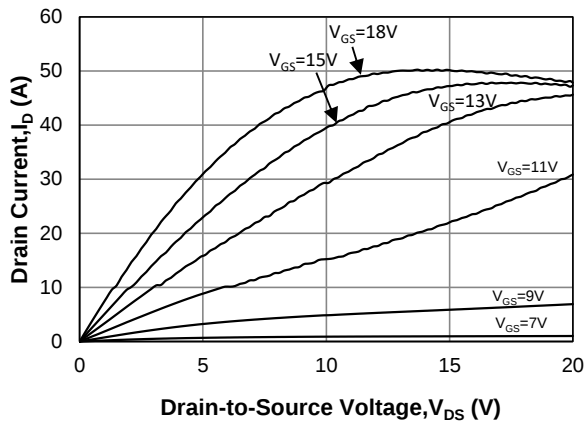


Fig 2. Output Characteristics ($T_j = 25^\circ\text{C}$)

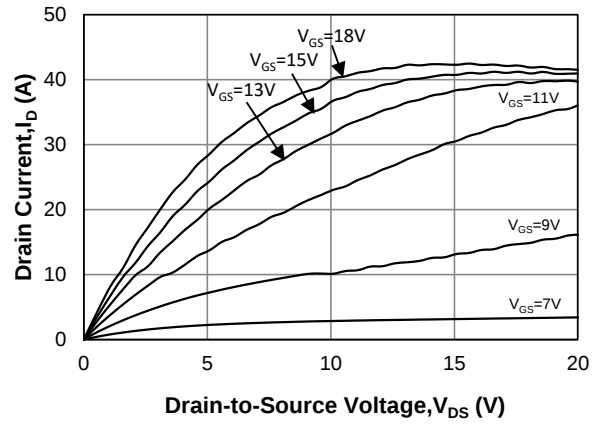


Fig 3. Output Characteristics ($T_j = 175^\circ\text{C}$)

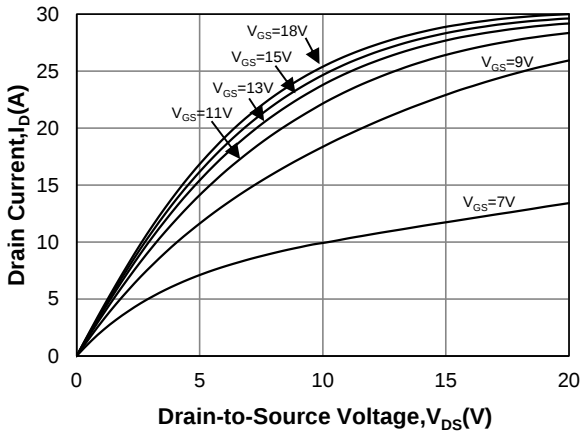


Fig 4: $R_{ds(on)}$ vs. Temperature

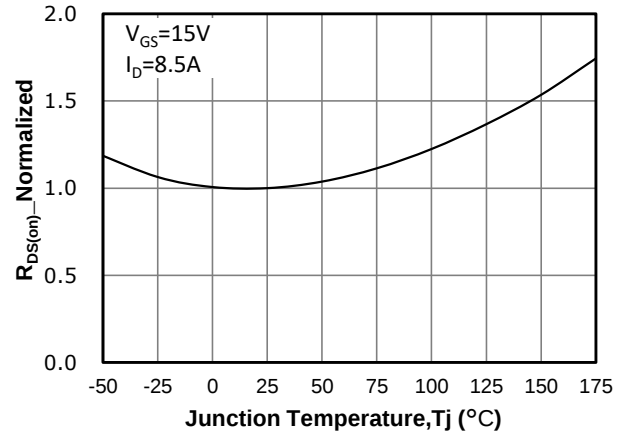


Fig 5: On-Resistance vs. Drain Current For Various Temperatures

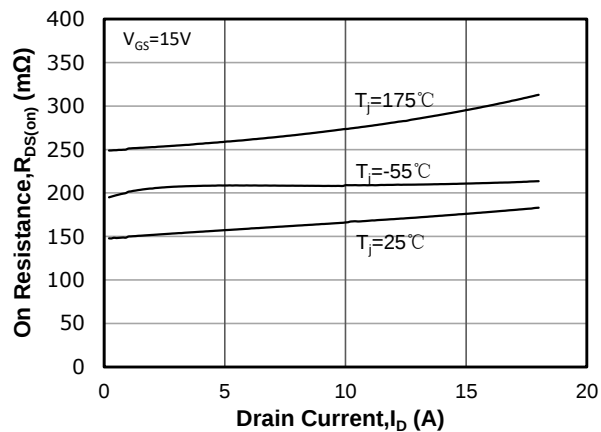


Fig 6: $R_{ds(on)}$ vs. Temperature For Various Gate Voltage

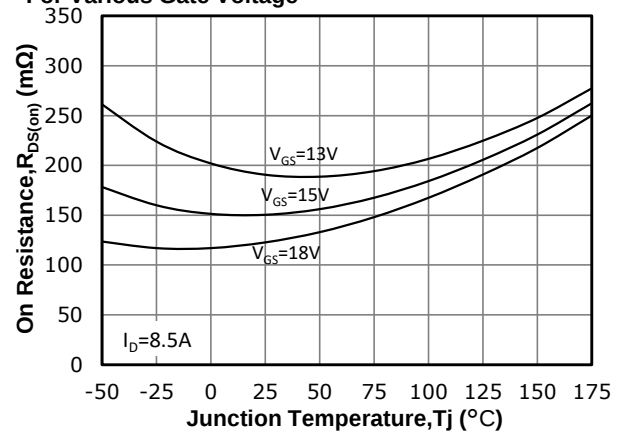


Fig 7: Transfer Characteristics

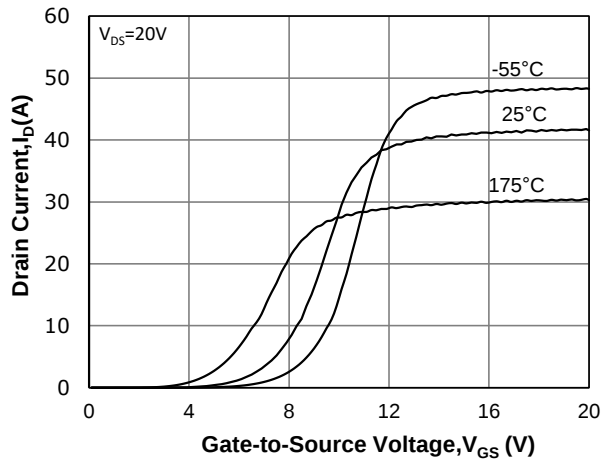


Fig 8: Body-diode Forward Characteristics For Various Temperatures

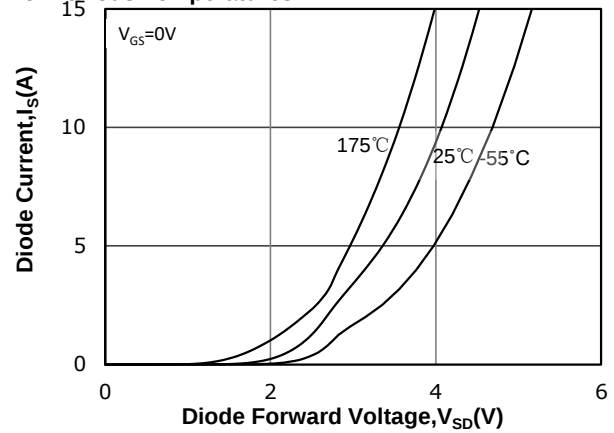


Fig 9: $V_{GS(th)}$ Vs T_j Characteristics

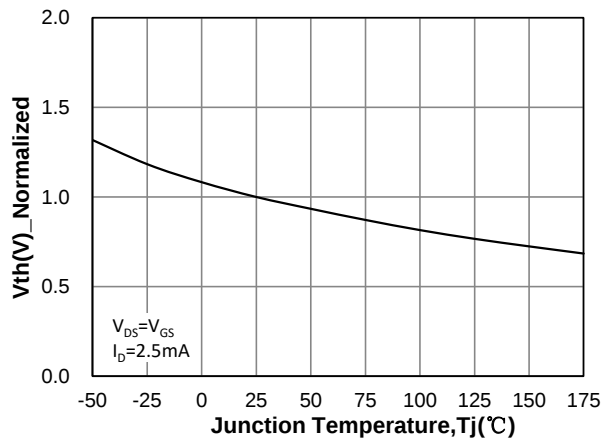


Fig 10: 3rd Quadrant Characteristic at $25^\circ C$

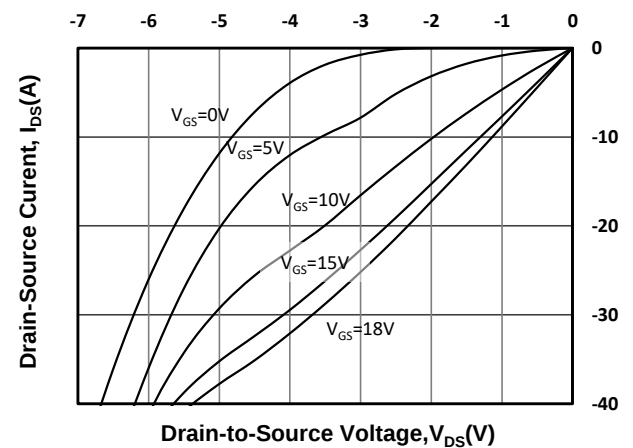


Fig 11: Gate Charge Characteristics

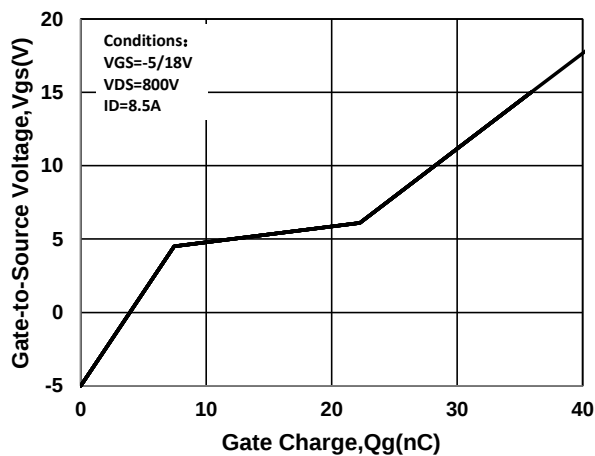


Fig 12: Capacitance Characteristics

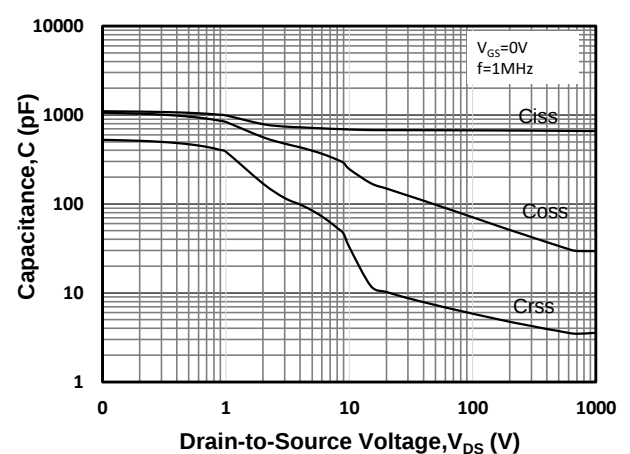


Fig 13: Continuous Drain Current vs. Case Temperature

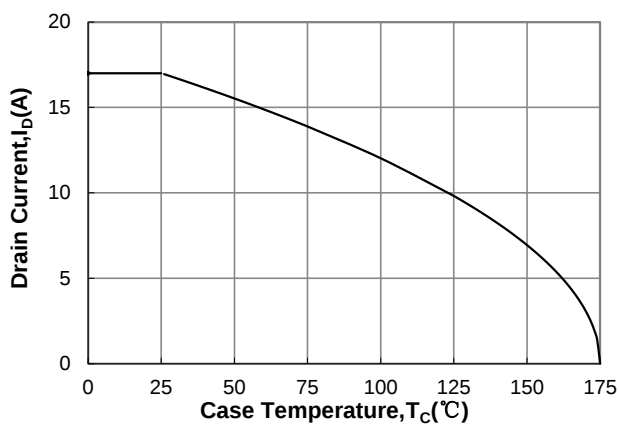


Fig 14: Maximum Power Dissipation vs. Case Temperature

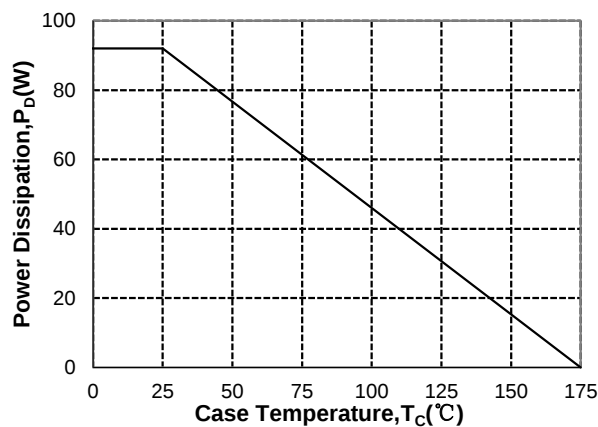


Fig 15: Safe Operating Area

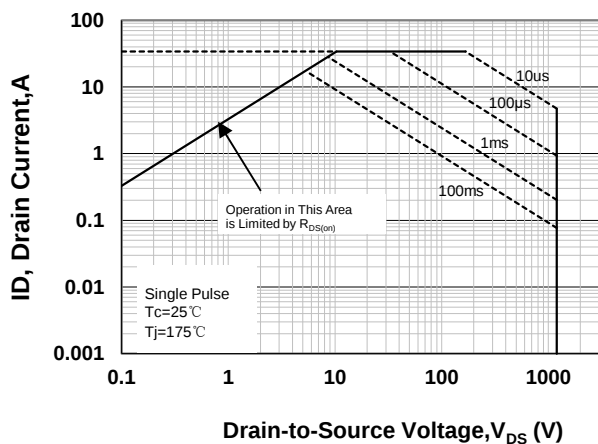


Fig 16: Output Capacitor Stored Energy

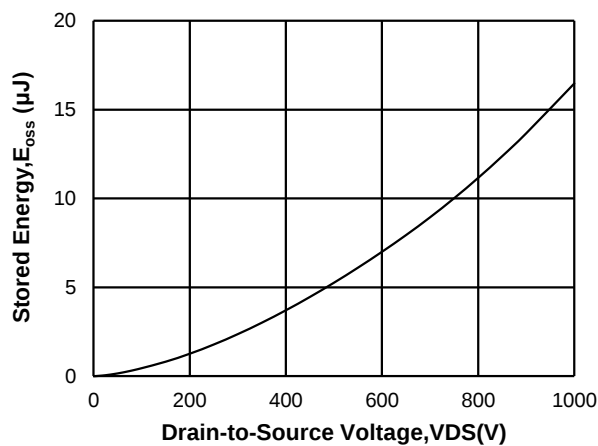
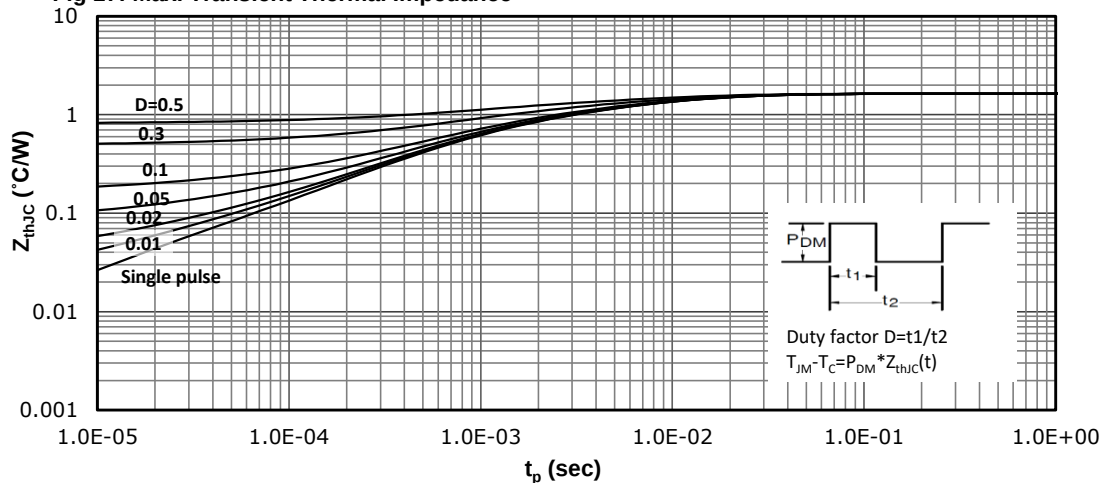
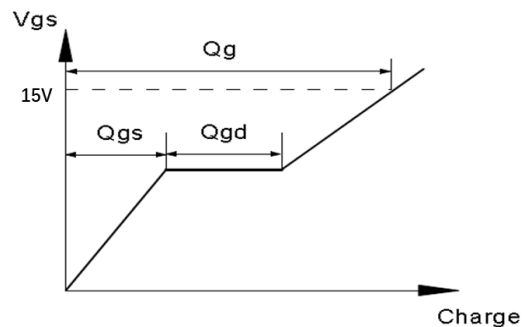
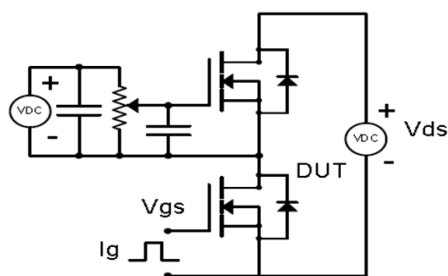


Fig 17: Max. Transient Thermal Impedance

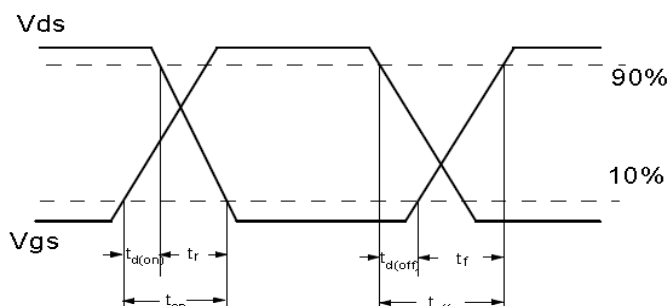
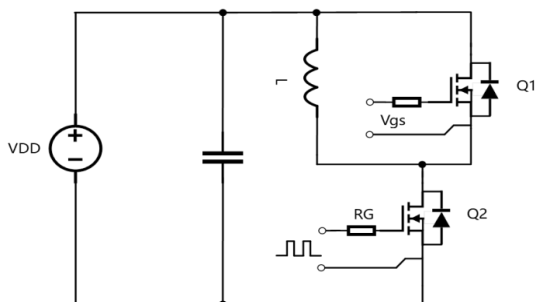


Test Circuit & Waveform

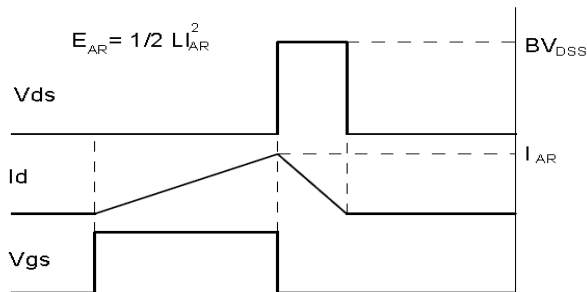
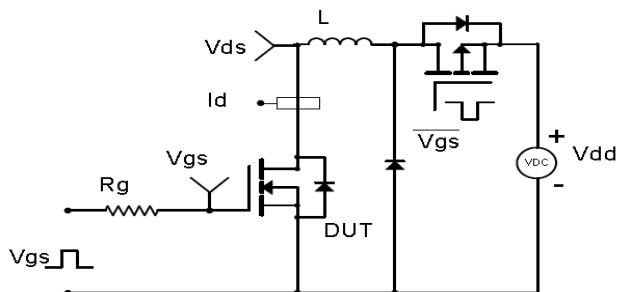
Gate Charge Test Circuit & Waveform



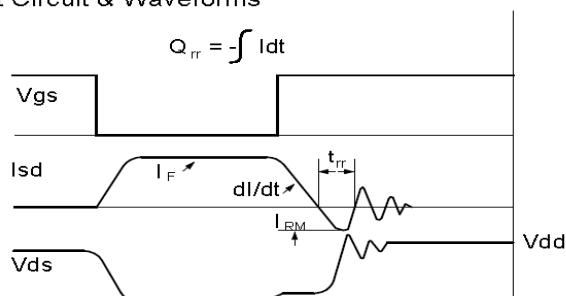
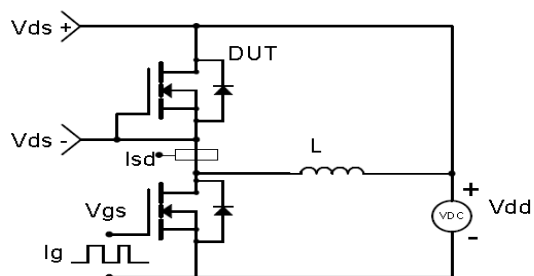
Resistive Switching Test Circuit & Waveforms



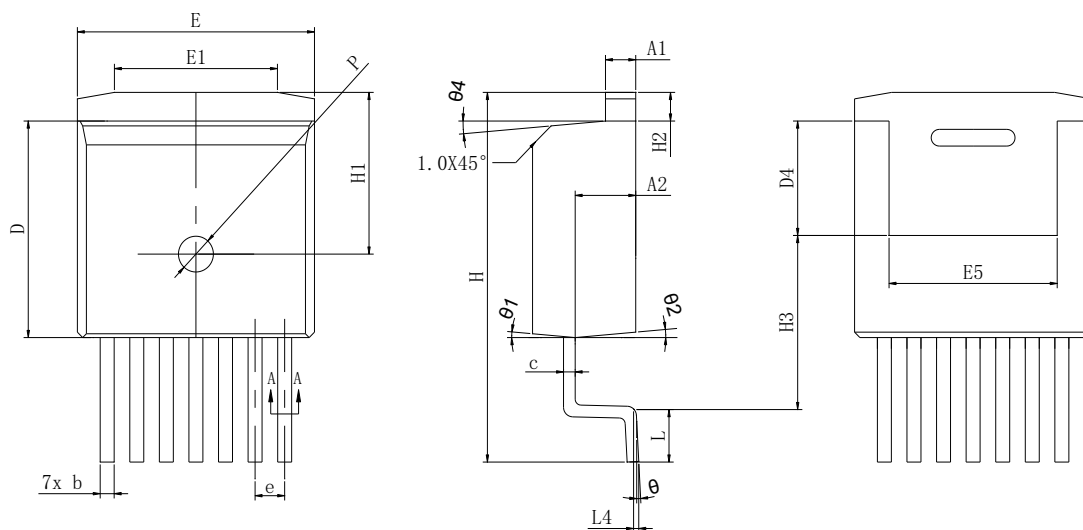
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Package Outline: TO-263US-7



Items	Values(mm)	
	MIN	MAX
A	4.2	4.6
A1	1.1	1.4
A2	2.4	2.8
A3	0	0.3
b	0.5	0.8
c	0.4	0.7
D	8.8	9.3
D4	4.5	5.05
e	1.27BSC	
E	9.8	10.4
E1	6.5	7.5
E5	6.72	7.72
H	14.8	16.2
H1	6.38	7.18
H2	0.9	1.5
H3	6.8	7.8
L	1.8	2.6
L4	0.25	
P	1.3	1.7
θ	0°	10°
θ1	2°	9°
θ2	2°	9°
θ4	2°	9°

Revision History

Revision	Date	Major changes
1.0	2024/5/31	Release of formal version

Disclaimer

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